



Form: PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1816	SERIAL NO. 09/955632			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT KUNAL R. PAREKH, ET AL.				
				FILING DATE 9-18-01 FILED CONCURRENTLY	GROUP 2813			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
yfr	AA	5,338,700	08/94	Dennison et al.				
	AB	5,401,681	03/95	Dennison				
	AC	6,015,983	01/00	Parekh				
	AD	5,981,334	11/99	Chien et al.				
	AE	5,981,333	11/99	Parekh et al.				
	AF	5,923,973	07/99	Chen et al.				
	AG	5,913,129	06/99	Wu et al.				
	AH	5,885,866	03/99	Chen				
	AI	5,874,335	02/99	Jenq et al.				
	AJ	5,763,286	06/98	Figura et al.				
yfr	AK	6,037,220	03/00	Chien et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
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	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
yfr	AR		Aoki, Masami, et al., "Fully Self-Aligned 6F ² Cell Technology For Low Cost 1 Gb DRAM", <i>Symposium</i>					
			On VLSI Technology Digest of Technical Papers, IEEE, pp. 22-23 (1996)					
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
				11/1/02				
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				FILING DATE <u>9-18-01</u>		GROUP <u>2813</u>		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
yz	AA	6,034,391	03/00	Tobita				
	AB	5,897,352	04/99	Lin et al.				
	AC	5,745,336	04/98	Saito et al.				
	AD	5,686,747	11/97	Just et al.				
	AE	5,383,150	01/95	Nakamura et al.				
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	AG	5,597,756	01/97	Fazan et al.				
	AH	5,639,689	06/97	Woo				
	AI	5,663,085	09/97	Tanigawa				
	AJ	5,418,180	05/95	Brown				
	yz	AK	5,340,765	08/94	Dennison et al.			
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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	AT							
EXAMINER					DATE CONSIDERED <u>11/1/01</u>			
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Form PTU-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1816		SERIAL NO. 09055,633	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT KUNAL R. PAREKH, ET AL.		GROUP 2813	
				FILING DATE September 18, 2001			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date (if Appropriate)
Y Y	AA	6,114,200	09-05-00	Yew et al.	7		
	AB	6,037,216	03/14/00	Lia et al.	11		
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	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
AK							
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL						
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	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER YPSM				DATE CONSIDERED 11/1/02			
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